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DUAL DIGIT LED DISPLAY (0.30 Inch)

**LDD305/64-XX**

DATA SHEET

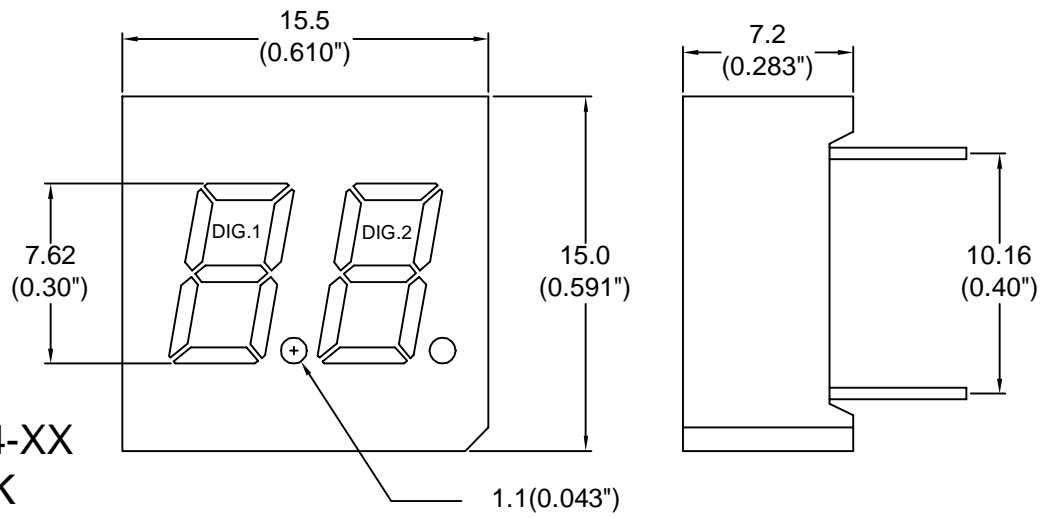
DOC. NO : QW0905-LDD305/64-XX

REV. : A

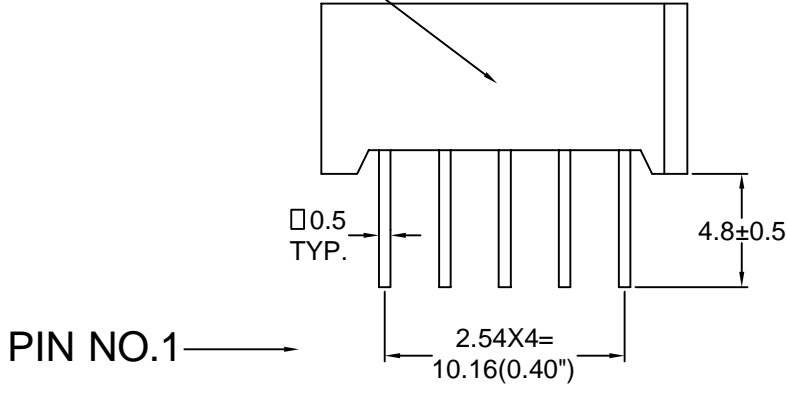
DATE : 28 - Jun - 2005



Package Dimensions



LDD305/64-XX  
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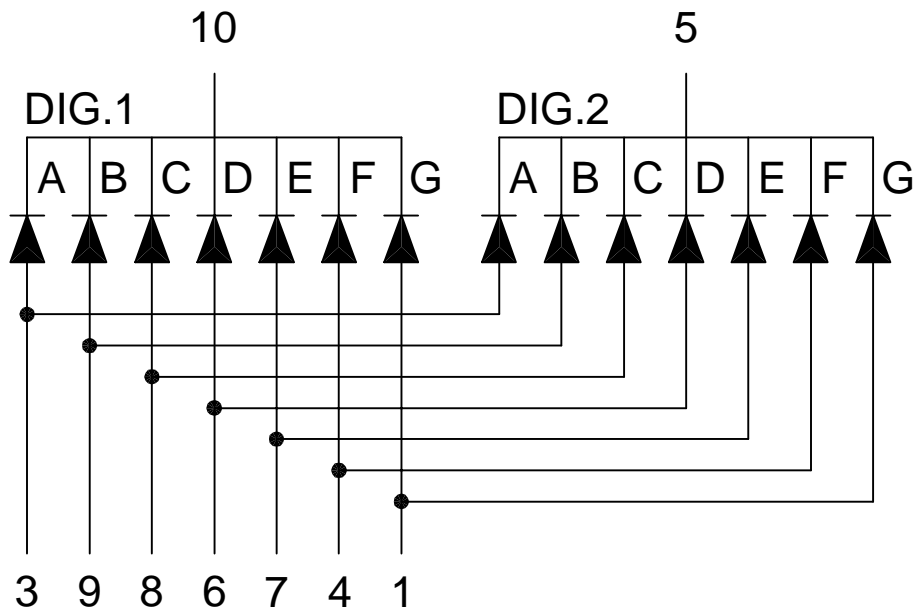


Note : 1.All dimension are in millimeters and (Inch) tolerance is  $\pm 0.25$ mm unless otherwise noted.  
 2.Specifications are subject to change without notice.

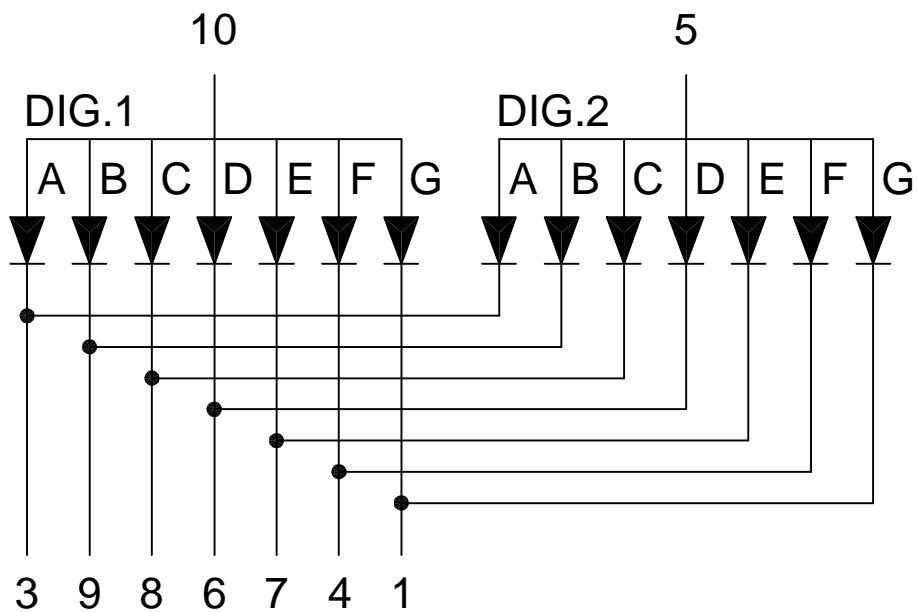


Internal Circuit Diagram

LDD3054-XX



LDD3064-XX





### Electrical Connection

Connection To Electrical Schematic			
Electrical connection			
PIN NO.	LDD3054-XX	PIN NO.	LDD3064-XX
1	Anode G	1	Cathode G
2	No Pin	2	No Pin
3	Anode A	3	Cathode A
4	Anode F	4	Cathode F
5	Common Cathode Dig.2	5	Common Anode Dig.2
6	Anode D	6	Cathode D
7	Anode E	7	Cathode E
8	Anode C	8	Cathode C
9	Anode B	9	Cathode B
10	Common Cathode Dig.1	10	Common Anode Dig.1



Absolute Maximum Ratings at Ta=25

Parameter	Symbol	Ratings	UNIT
		E	
Forward Current Per Chip	IF	30	mA
Peak Forward Current Per Chip (Duty 1/10,0.1ms Pulse Width)	IFP	120	mA
Power Dissipation Per Chip	PD	100	mW
Reverse Current Per Any Chip	Ir	10	μ A
Operating Temperature	Topr	-25 ~ +85	
Storage Temperature	Tstg	-25 ~ +85	
Solder Temperature 1-16 Inch Below Seating Plane For 3 Seconds At 260			

Part Selection And Application Information(Ratings at 25 )

PART NO	CHIP		common cathode or anode	P (nm)	(nm)	Electrical					IV-M
	Material	Emitted				Vf(v)			Iv(mcd)		
						Min.	Typ.	Max.	Min.	Typ.	
LDD3054-XX	GaAsP/GaP	Orange	Common Cathode	635	45	1.7	2.1	2.6	0.8	1.35	2:1
LDD3064-XX			Common Anode								

Note : 1.The forward voltage data did not including ±0.1V testing tolerance.  
2. The luminous intensity data did not including ±15% testing tolerance.



### Test Condition For Each Parameter

Parameter	Symbol	Unit	Test Condition
Forward Voltage Per Chip	V <sub>f</sub>	volt	I <sub>f</sub> =20mA
Luminous Intensity Per Chip	I <sub>v</sub>	mcd	I <sub>f</sub> =10mA
Peak Wavelength	λ <sub>p</sub>	nm	I <sub>f</sub> =20mA
Spectral Line Half-Width		nm	I <sub>f</sub> =20mA
Reverse Current Any Chip	I <sub>r</sub>	μ A	V <sub>r</sub> =5V
Luminous Intensity Matching Ratio	IV-M		



### Typical Electro-Optical Characteristics Curve

E CHIP

Fig.1 Forward current vs. Forward Voltage

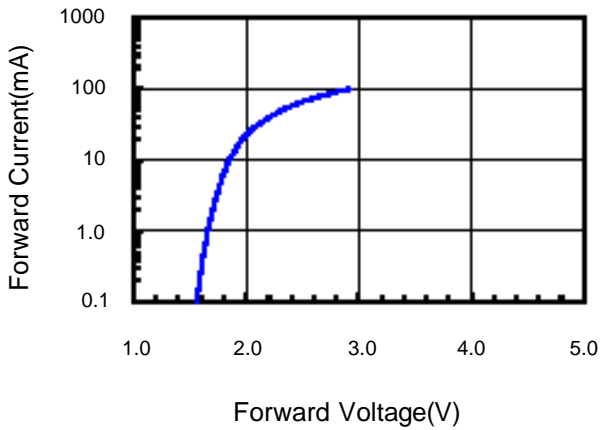


Fig.2 Relative Intensity vs. Forward Current

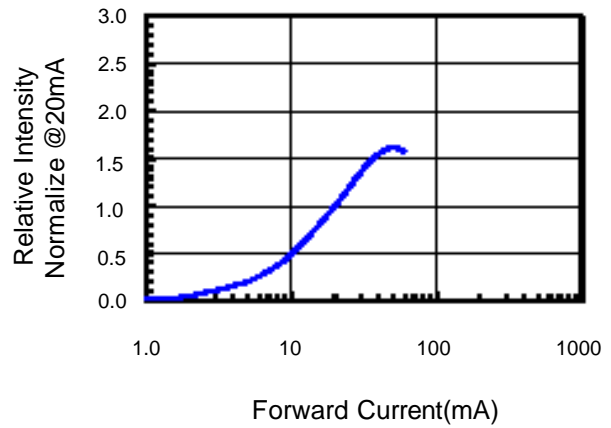


Fig.3 Forward Voltage vs. Temperature

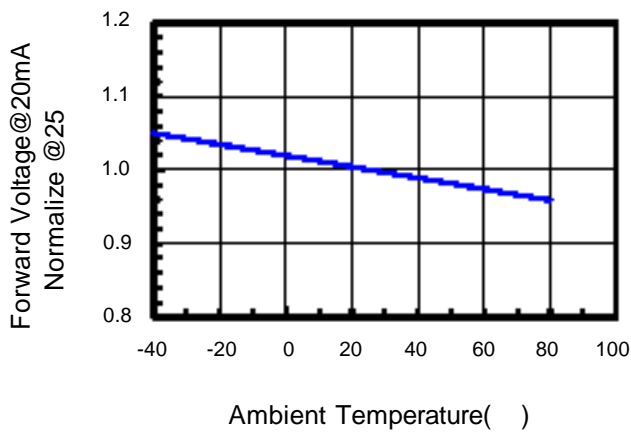


Fig.4 Relative Intensity vs. Temperature

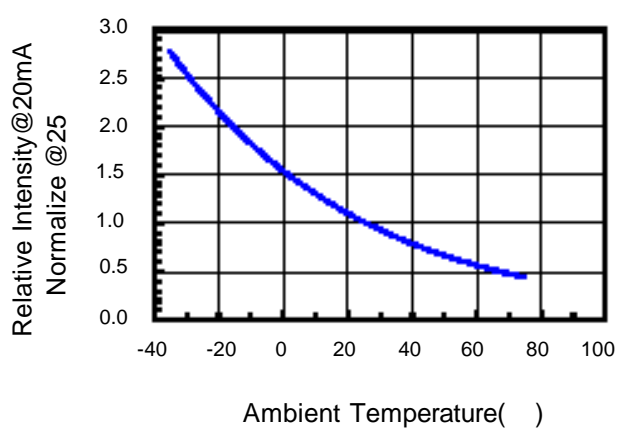
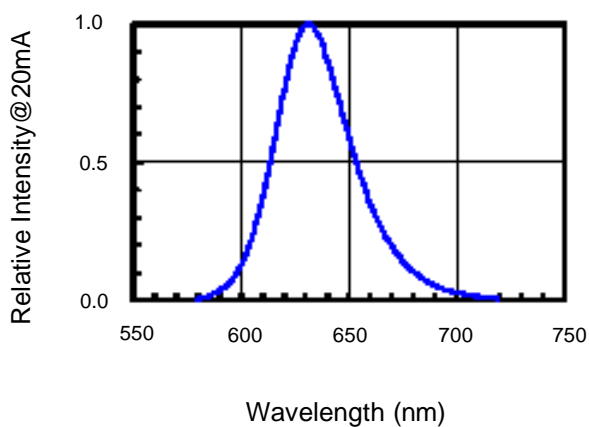


Fig.5 Relative Intensity vs. Wavelength





Reliability Test:

Test Item	Test Condition	Description	Reference Standard
Operating Life Test	1.Under Room Temperature 2.If=10mA 3.t=1000 hrs (-24hrs, +72hrs)	This test is conducted for the purpose of detemining the resisance of a part in electrical and themal stressed.	MIL-STD-750: 1026 MIL-STD-883: 1005 JIS C 7021: B-1
High Temperature Storage Test	1.Ta=105 ±5 2.t=1000 hrs (-24hrs, +72hrs)	The purpose of this is the resistance of the device which is laid under ondition of high temperature for hours.	MIL-STD-883:1008 JIS C 7021: B-10
Low Temperature Storage Test	1.Ta=-40 ±5 2.t=1000 hrs (-24hrs, +72hrs)	The purpose of this is the resistance of the device which is laid under condition of low temperature for hours.	JIS C 7021: B-12
High Temperature High Humidity Test	1.Ta=65 ±5 2.RH=90%~95% 3.t=240hrs ±2hrs	The purpose of this test is the resistance of the device under tropical for hous.	MIL-STD-202:103B JIS C 7021: B-11
Thermal Shock Test	1.Ta=105 ±5 & -40 ±5 (10min) (10min) 2.total 10 cycles	The purpose of this is the resistance of the device to sudden extreme changes in high and low temperature.	MIL-STD-202: 107D MIL-STD-750: 1051 MIL-STD-883: 1011
Solder Resistance Test	1.T.Sol=260 ±5 2.Dwell time= 10 ±1sec.	This test intended to determine the thermal characteristic resistance of the device to sudden exposures at extreme changes in temperature when soldering the lead wire.	MIL-STD-202: 210A MIL-STD-750: 2031 JIS C 7021: A-1
Solderability Test	1.T.Sol=230 ±5 2.Dwell time=5 ±1sec	This test intended to see soldering well performed or not.	MIL-STD-202: 208D MIL-STD-750: 2026 MIL-STD-883: 2003 JIS C 7021: A-2